

Search Notes

Application/Control No.

10/615,229

Examiner

Y. Lee

Applicant(s)/Patent under
Reexamination

ITOI ET AL.

Art Unit

2621

SEARCHED

Class	Subclass	Date	Examiner
375	240.26	4/25/2007	YL
348	48		
H04N	7/12		
update	search	9/11/2007	YL
update	search	1/29/2008	YL
375	240.03		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	240.26	1/30/2008	YL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR